

INPADOCDB

(International Patent Documentation DataBase)

Subject Coverage • All areas of science and technology, i.e., all classes of the International Patent Classification

File Type Bibliographic

Features

Thesauri	Cooperative Patent Classification (/CPC), International Patent Classification (/IPC), and US National Patent Classification (/NCL, /INCL)			
Alerts (SDIs)	Weekly or monthly (Weekly is the default)			
CAS Registry Number® Identifiers	<input type="checkbox"/>	Page Images	<input type="checkbox"/>	STN® AnaVist™ <input type="checkbox"/>
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Learning Database	<input checked="" type="checkbox"/>	Structures	<input type="checkbox"/>	

Record Content

- Bibliographic and family data of patent documents and utility models of more than 95 patent-issuing organizations including the European Patent Office (EPO) and the World Intellectual Property Organization (WIPO).
- Legal status data of 63 patent-issuing organizations (53 countries + from 10 countries of the national phases PCT/EP).
- Abstracts are provided for 32.5 million records.
- First page images are available for the following patent authorities: CH (1944-), DE (1955-), EP (1978-), FR (1961-), GB (1897-), JP (1952-), US (1955-), and WO (1978-).
- Calculated expiration dates are provided for granted IP rights for 41 patent authorities, see HELP XPD for details.
- Note: The accession number can change due to corrections/updates of patent relevant numbers and codes.

File Size

More than 94.7million records (applications) including patent families with about 120 million publications in more than 62 million international patent families from 1782 to the present (01/2020)

More than 300 million legal status data in more than 60 million records from 1968 to the present (01/2020)

More than 293 million patent and non-patent citations in more than 31 million patent families are available for 37 authorities from 1920 to the present (01/2020)

Citing patent information is available for more than 19.4 million applications

Coverage 1790-present

Updates Weekly with 130,000-600,000 records and 120,000-500,000 legal status data

Language English

Database Producer

European Patent Office
 Vienna Sub Office
 P.O. Box 90
 Austria
 Phone: +43 1 52126-0
 Fax: +43 1 52126-5491
 Email: patentdata@epo.org
 Copyright Holder

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 - INPADOC Legal Status Service
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 - STNGUIDE
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http://www.stn-international.com/inpadocdb_inpafamdb_handbook.html
-

- Clusters**
- ALLBIB
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 - CORPSOURCE
 - HPATENTS
 - PATENTS
- [STN Database Clusters](#) information (PDF)
-

Pricing Enter HELP COST at an arrow prompt (=>).

Search and Display Field Codes

Fields that allow left truncation are indicated by an asterisk (*).

Bibliographic Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index* (contains single words from title (TI) and abstract (AB) fields)	None or /BI	S TUBULAR HEAT EXCHANG? S ALUM? (S) COAT? S ?MAGNET? S ?METHYL?(T)?AMINO? S (DRILLING(W)PROCESS)/AB	AB, ABDE, ABFR, ABES, ABOL, ABS, TI
Abstract* (contains AB, ABDE, ABES, ABFR, ABOL) (1)	/AB		AB, ABDE, ABES, ABFR, ABOL
Abstract Language (ISO code and text)	/AL	S DUTCH/AL	ALL, ALLO, IMAX, MAX, MAXO
Accession Number	/AN	S 12345678/AN	AN
Application Country (WIPO code and text)	/AC	S WO/AC AND (INLAND(W)STEEL)/PA	AI
Application Date (2)	/AD	S 19840705/AD	AI
Application Kind Code	/AK	S WOW/AK	AI, AIT
Application Kind Code Text	/AIT	S MWA/AIT	AIT
Application Number	/AP	S ZW1981-215/AP	AI
Application Year (2)	/AY	S 1988/AY AND SIEMENS/PAS	AI
Calculated Expiration Date (2)	/XPD	S XPD=AUG 2013	XPD
Calculated Expiration Year (2)	/XPY	S 2010-2011/XPY	XPY
Changes (Indicator for the changes in the last update)	/CHG	S FCL C/CHG	CHG
Citation Category	/CAT	S X/CAT	REN, REP, RE
Cited Application Country	/AC.D	S AT/AC.D	REAI
Cited Application Kind Code	/AK.D	S ATA/AK.D	REAI
Cited Application Number	/AP.D	S AT920000957/AP.D	REAI
Citing Patent Country (WIPO code and text)	/PC.G	S AT/PC.G	CGP
Citing Patent Number	/PN.G	S BG65643/PN.G	CGP
Cooperative Patent Classification	/CPC	S D03D0015-0011/CPC	CPC
CPC, Action Date (2)	/CPC.ACD	S 20130101/CPC.ACD	CPC.TAB
CPC, Combination Set Data (11)	/CPC.CS	S A61K0009/CPC.CS	CPC.TAB
CPC, Keyword Terms	/CPC.KW	S INVENTION/CPC.KW	CPC.TAB
CPC, Version (2)	/CPC.VER	S 20130101/CPC.VER	CPC.TAB
Data Availability	/DAV	S NOT-PRINTED-WITH-GRANT/DAV	DAV
Data in Force (2,4)	/DF	S 20070401/DF	DF
Designated States	/DS	S W JP/DS	DS
Document Type (code and text)	/DT (or /TC)	S U/DT AND UNILEVER/PAS	DT
Entry Date (2,5)	/ED	S L1 AND ED>1 JAN 2007	ED
Entry Date New Patent Family (2)	/EDF	S 20070321/EDF	EDF
Entry Date new publication and/or New Legal Status (2)	/EDLS	S EDLS=20070419	not displayed
Entry Date Patent (2,5)	/EDP	S 20061130/EDP	EDP
Entry Date Priority (2,5)	/EDPR	S 20070401-20070429/EDPR	PRAI
Entry Week (INPADOC) (2,6)	/EW	S 200801/EW	EW
Field Availability	/FA	S L7 AND DS/FA	FA
Filing Country for PCT Application	/AC.WO	S FR/AC.WO	AI
Filing Country for PCT Priorities (WIPO code and text)	/PRC.WO	S DE/PRC.WO	PRAI
Filing Details	/FDT	S DED1/FDT	FDT

INPADOCDB

Bibliographic Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
International Patent Classification (contains ICM, ICS, ICA, ICI, IPCI, IPCR)	/IPC	S H05B0006-36+NT/IPC S H05B0006-36-H05B0006-44/IPC	IC, ICA, ICI, ICM, ICS, IPCI, IPCR IN
Inventor	/IN (or /AU)	S NICKOLA RICHARD?/IN	IN
Inventor Address	/INA	S HEIDELBERG/INA	INA
Inventor, Country (WIPO code and text)	/IN.CNY	S GB/IN.CNY	INS
Inventor INPADOC Standard IPC (contains ICM and ICS), Version 1-7 (7)	/INS	S AGARWAL S?/INS	INS
IPC, Action Date	/IC	S C07H019-16/IC	IC
IPC, Additional (supplementary) Version 1-7 (7)	/IPC.ACD	S 13 JAN 2006/IPC.ACD	IPC.TAB
IPC, Index (complementary) Version 1-7 (7)	/ICA	S A61K037-64/ICA	ICA
IPC, Keyword Terms	/ICI	S (C12P019-40(L)C12R001:465)/ICI	ICI
IPC, Main, Version 1-7 (7)	/IPC.KW	S INITIAL/IPC.KW	IPC.TAB
IPC, Secondary (7)	/ICM	S C23C001-08/ICM	ICM
IPC, Version from IC	/ICS	S C12P019-40/ICS	ICS
IPC, Version from IPC	/IC.VER	S 7/IC.VER AND L5	IC.VER, IC
Japanese Patent Classification (FI-Terms)	/IPC.VER	S 200601/IPC.VER	IPC.TAB
Japanese Patent Classification (F-Terms)	/FCL (or /JPC)	S A01B0001-24 B/FCL	FCL
Language (ISO code and text)	/FTRM (or /FTERM, or /FTCLA, or /JPCLA)	S 5H030/AA00/FTRM	FTRM
Language of Filing (ISO code and text)	/LA	S DE/LA	LA
Locarno Classification	/LAF	S FR/LAF	LAF
Non-Patent Literature XP- Document Number	/LCL	S 3001/LCL	LCL
Origin of Citation	/REXP	S XP002235691/REXP	REXP
Other National Classifications (10)	/SRT	S EXA/SRT	REN, REP, REXP
Patent Assignee (8)	/OCL	S 81C,27/OCL	OCL
Patent Assignee Address	/PA	S INLAND STEEL/PA	PA
Patent Assignee INPADOC Standard (8)	(or /CS)	S BROWN WILLIAMSON/CS	
Patent Assignee, Country	/PAA	S US/PAA AND EASTMAN KODAK/PAS	PAA
Patent Country	/PAS	S INLAND STEEL CO?/PAS	PAS
(WIPO code and text)	/PA.CNY	S (BROWN(S)TOBACCO)/PAS	
Patent Information Publication Type	/PC	S GB/PA.CNY	PAS
Patent Kind Code	/PIT	S DE/PC AND IBM/PAS AND 1988/PY	PI
Patent Number (3)	/PK	S ARA1/PIT	PIT
Patent Number/Kind Code	/PN	S ZWA1/PK	PI
Patent Status	/PNK	S F1990202U/PN	PNK
Priority Country	/STA	S WO2009006253A2/PNK	STA
(WIPO code and text)	/PRC	S GRANTED/STA AND LASER/TI	PRAI
Priority Date (2)	/PRD	S JP/PRC AND 19880101/PRD	PRAI
Priority Date, First (2)	/PRDF	S MARCH 2009/PRDF	PRAI
Priority Kind Code	/PRK	S DEA/PRK	PRAI

Bibliographic Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Priority Kind Code	/PRK	S DEA/PRK	PRAI
Priority Kind Text	/PRAIT	S ARA PATENT APPLICATION/PRAIT	PRAIT
Priority Number (3)	/PRN	S US1990-184420/PRN	PRAI
Priority Year (2)	/PRY	S 1998/PRY AND US/PRC	PRAI
Priority Year, First (2)	/PRYF	S GB/PC AND 1998/ PRYF	PRAI
Publication Date (2)	/PD	S 19990104/PD	PI
Publication Year (2)	/PY	S 1999/PY	PI
Reference Count	/REC (or /RE.CNT)	S 8/REC	REC
Referenced Non-Patent Literature	/REN	S MAYER/REN	REN
Referenced Patent Country	/RPC (or /PC.D)	S WO/RPC	RE, REP
Referenced Patent Date	/RPD (or /PD.D)	S 19730919/RPD	REP
Referenced Patent Kind Code	/RPK (or /PK.D)	S EPA/RPK	REP
Referenced Patent Number	/RPN (or /PN.D)	S EP1234567/RPN	REP
Referenced Patent Year	/RPY (or /PY.D)	S 2010/RPY	REP
Search Report Office (WIPO code and text)	/SRO	S CH/SRO	REP
Title*	/TI	S (APPARAT? (S) SMOKE (S) FILTER#)/TI	TI
Title Language (ISO code and text)	/TL	S EN/TL S ENGLISH/TL	TL
Update Date (2)	/UP	S L1 AND UP>20070102	UP
Update Date All Patent Changes (2)	/UPM	S L1 AND 20070222/UPM	not displayed
Update Date Classifications (2)	/UPCC	S L1 AND UPCC>20070222	UPALL
Update Date for combined or split Patent Family (9)	/UPFC	S UPFC=OCT 2009	UPALL
Update Date Legal Status (2)	/UPLS	S UPLS=20070222	LS, LSUP
Update Date New Publication and/or Legal Status Changes of the family (2)	/UPFE	S 20070321/UPFE	UPALL
Update Date of the BIB fields (2)	/UPBB	S L1 AND UPBB>20070222	UPALL
Update Date Patent Family (2) (All Updates)	/UPFA	S 20070329/UPFA	UPALL
Update Date New Patent Family Record (2)	/UPFD	S 20070215/UPFD	UPALL
Update Date Patent Family Legal Status (2)	/UPFL	S 20070321/UPFL	UPALL
Update Date Patent Family Publication Level (2)	/UPFP	S 20070222/UPFP	UPALL
Update Date Patent Family Bibliographic (2)	/UPFB	S 20070215/UPFB AND L7	UPALL
Update Week (INPADOC Week) (2)	/UW	S UW=200641 AND L3	UW
US National Classification, Current	/NCL	S 455289000/NCL	NCL
US National Classification, Current (main)	/NCLM	S 455289000/NCLM	NCL

Bibliographic Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
US National Classification, Current (secondary)	/NCLS	S 455289000/NCLS	NCL
US National Classification, Issued	/INCL	S 455289000/INCL	INCL
US National Classification, Issued (main)	/INCLM	S 455289000/INCLM	INCL
US National Classification, Issued (secondary)	/INCLS	S 455289000/INCLS	INCL

- (1) This field is available for selected countries and patent publications.
- (2) Numeric search field that may be searched using numeric operators or ranges.
- (3) Either STN or Derwent format may be used.
- (4) For German Utility Models: Advertisement of registration.
- (5) Available since 2007.
- (6) Available since week 200641
- (7) Search in IPC8 format also available.
- (8) Search with implied (S) proximity is available.
- (9) Available since September 2009.
- (10) Selected coverage for DE, GB, CH, CA, AT, SE, DK, BR, MX, AU, ES, NL.
- (11) No expand is available in this field. A special search edit triggers a search in /CPC combined with (T) proximity and CPC.KW. e.g. S A61K0009/CPC.CS is searched as (A61K0009/CPC (T) COMBINATION SET/CPC.KW)

Legal Status Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Entry Date New Publication and/or New Legal Status (1)	/EDLS	S EDLS=FEB 2009	not displayed
Entry Week Legal Status	/EWLS	S 200641-200642/EWLS	LS2
Legal Status Basic Index (contains legal status agent (LSAG), legal status free format text (LSFT), legal status inventor (LSIN), legal status patent opponent (LSOP), and legal status patent assignee (LSPA) fields)	/LSBI	S LASER?/LSBI S ANACOMP/LSBI S OPPOSITE/LSBI	LS
Legal Status Code (code and text)	/LSC	S EP111L/LSC	LS
Legal Status Code Category	/LSC2	S NIF/LSC2	LS
Legal Status Code Country (WIPO code and text)	/LSCC	S BE/LSCC	LS
Legal Status Country (WIPO code and text)	/LSCY	S UNITED KINGDOM/LSCY	LS
Legal Status Date in Force (1)	/LSDF	S LSDF=20050109	LS
Legal Status Date INPADOC GAZETTE (1)	/LSD	S LSD=JAN 2002	LS
Legal Status Designated States (WIPO code and text)	/LSDS	S AU/LSDS S AUSTRALIA/LSDS	LS
Legal Status Free Format Text	/LSFT	S TELECOMMUNICATION/LSFT	LS
Legal Status Indicator	/LSCI	S POSITIVE/LSCI AND L3	LS
Legal Status IPC	/LSIC	S 41J320/0/LSIC	LS
Legal Status Licensee	/LSLI	S BAYER/LSLI	LS
Legal Status Patent Assignee (2)	/LSPA	S (MAN CERAMICS)/LSPA	LS

Legal Status Search Fields (cont'd)

Search Field Name	Search Code	Search Examples	Display Codes
Legal Status Patent Inventor	/LSIN	S MAYER, BERND/LSIN S (MAYER(S)BERND)/LSIN	LS
Legal Status Patent Opponent	/LSOP	S SIEMENS AG/LSOP	LS
Legal Status, Payment Year (1)	/LSPMY	S 18/LSPMY	LS
Legal Status Publication Country (WIPO code and text)	/LSPC	S CA/LSPC S CANADA/LSPC	LS
Legal Status Publication Date (1)	/LSPD	S LSPD=JAN 1998	LS
Legal Status Publication Kind Code	/LSPK	S ES00/LSPK	LS
Legal Status Publication Number	/LSPN	S EP200212/LSPN	LS
Legal Status Publication Year (1)	/LSPY	S 1999-2000/LSPY	LS
Legal Status Represent./Agent	/LSAG	S (LORENZ AND PHILIPPS)/LSAG	LS
Legal Status Code Text	/LSTX	S CORRECTION/LSTX	LS
Legal Status SPC Number	/LSSPC	S EU/1/00/129/001/LSSPC	LS
Legal Status SPC, Expiry Date (1)	/LSSPC.XD	S LSSPC.XD>2005	LS
Legal Status SPC, Extension Date (1)	/LSSPC.EX	S 20010910/LSSPC.EX	LS
Legal Status SPC, Filing Date (1)	/LSSPC.FD	S 19950101-19961231/LSSPC.FD	LS
Update Legal Status (1)	/UPLS	S 20070208/UPLS	LS, LSUP

(1) Numeric search field that may be searched using numeric operators or ranges.

(2) Search with implied (S) proximity is available.

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Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group (1)	/APPS	/AP, /PRN	S DE1984-3400052/APPS S 1984DE-3400052/APPS	AI, PRAI
Inventor Group	/INSS	/IN, /INS, /LSIN	S MEIER/INSS	IPC
US National Classification	/NCLALL	/NCL, /INCL	S 901014000/NCLALL	NCL, INCL
Patent Assignee Group	/PASS	/PA, /PAS, /LSPA	S MEIER/PASS	PI
Patent Countries	/PCS	/PC, /DS	S BE/PCS	PI, DS
Patent Number Group (1)	/PATS	/PN, /RPN	S WO1989004114/PATS	PI, REP

(1) Either STN format or Derwent format may be used.

INPADOCDB**IPC THESAURUS**

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1-8, use the field code followed by the edition number, e.g., /IPC2 for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions.

Code	Content	Examples
ADVANCED (ADV) ALL BRO (MAN) BT BTn	Advanced Level Codes for the Core Level IPC Code All Associated Terms (BT, SELF, NT, RT) Complete Class Broader Term (SELF, BT) Broader Term (SELF, BT) up to the next n levels (n =1,2,...)	E A61K0066-02+ADVANCED/IPC E C01C003-00+ALL/IPC E C01C+BRO/IPC E C01F001-00+BT/IPC E C01F001-21+BT2/IPC
CORE (COR) ED HIE	Core Codes for the Advanced Level IPC Code Complete title of the SELF term and IPC manual Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E G08C0019-22+CORE/IPC E C01F001-00+ED/IPC E C011003-00+HIE/IPC
INDEX KT NEXT NT NTn	Complete title of the SELF term Keyword Term (catchwords) (SELF, KT) Next Classification Narrower Terms (SELF, NT) Narrower Terms (SELF, NT) down to the next n levels (n =1,2,...)	E C01F001-00+INDEX/IPC E CYANOGEN+KT/IPC E C01C001-00+NEXT5/IPC E C01C+NT/IPC E C01C+NT3/IPC
PREV PREV(n) RT (SIB) TI	Previous Code within the same class (SELF, PREV) Previous n classifications within the same class Related Terms (SELF, RT) Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01C001-12+PREV/IPC E C01C001-12+PREV10/IPC E C01C003-20+RT/IPC E C01F001-00+TI/IPC

CPC Thesaurus

This thesaurus is available in the /CPC search field. All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL AUTO (1) BT CODE	All usually required terms (BT, SELF, CODE, DEF) Automatic relationship (BT, SELF, CODE, DEF) Broader terms (BT, SELF) Classification Code (SELF, CODE)	E C12M0001-34H2+ALL/CPC E G01J003-443+AUTO/CPC E G01J0003-443+BT/CPC E SCRAPER BIASING MEANS+CODE/CPC
DEF HIE	Definition (SELF, DEF) Hierarchy terms (all broader and narrower terms) (BT, SELF, DEF, NT)	E B65G0045-16+DEF/CPC E A01B0001+HIE/CPC
KT MAX NEXT NEXT(n) NT PREV PREV(n) TI	Keyword terms (SELF, KT) All associated terms Next classification within the same class (SELF, NEXT) Next n classification within the same class Narrower terms Previous Code within the same class (SELF, PREV) Previous n classifications within the same class Complete Title of the SELF Term and Broader Terms (BT, SELF)	E LASER+KT/CPC E G01J0003-44B+MAX/CPC E A01B0001-24+NEXT/CPC E A01B0001-24+NEXT3/CPC E G05B0001-04+NT/CPC E G05B0019-418N1+PREV/CPC E G05B0019-418N1+PREV2/CPC E G05B0001-03+TI/CPC

(1) Automatic Relationship is SET OFF. In case of SET REL ON the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

US National Patent Classification (/NCL, /INCL) Thesaurus

The US National Patent Classification thesaurus is available online in the fields /NCL and /INCL. All relationship codes can be used with both the EXPAND and SEARCH commands.

Relationship Code	Content	Search Examples
ALL AUTO (1) BT CODE DEF HIE KT MAX NEXT NEXT(n) NT PREV PREV(n) TI	All usually required terms (BT, SELF, DEF, NT) Automatic relationship (BT, SELF, DEF, NT) Broader Terms (BT, SELF) Classification Code (SELF, CODE) Definition (SELF, DEF, DEF2, DEF3, DEF4) Hierarchy Terms (BT, SELF, DEF, NT) Keyword Terms (SELF, KT) All associated Terms (BT, SELF, DEF, DEF2, DEF3, DEF4, NT, KT) Next classification within the same class Next n classifications within the same class Narrower Terms (SELF, NT) Previous Code within the same class Previous n classifications within the same class Complete title including Broader Terms (SELF, BT, DEF (BT))	E 257E21685+ALL/NCL E 02416300R+AUTO/NCL E 02416300R+BT/NCL E APPAREL+CODE/NCL E G9B031001+DEF/NCL E 23548700+HIE/NCL E APPAREL+KT/NCL E G9B031000+MAX/NCL E G9B033035+NEXT/NCL E G9B033035+NEXT2/NCL S 257E21685+NT/NCL E 235462260+PREV/NCL E 235462260+PREV3/NCL E 052002110+TI/NCL

(1) Automatic Relationship is SET OFF. In case of SET REL ON the result of EXPAND or SEARCH without any relationship code is the same as described for AUTO.

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI PI. The fields are displayed or printed in the order requested.

All custom display fields provide the deduplicated content of all publications of a record (national family).

You can combine all display fields and all display formats with the qualifier .M to display the content for all publications of a record.

You can combine all display fields and all display formats with the qualifier .F to display the content for all family members (will be charged as a family display).

Hit-term highlighting is available for all fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB	Abstract in English	D AB
ABDE	Abstract in German	D ABDE
ABES	Abstract in Spanish	D ABES
ABEQ (1)	Display of an English equivalent abstract	D ABS
ABFR	Abstract in French	D ABFR
ABOL	Abstract in Other Language	D ABOL
AI (2)	Application Information	D AI
AIT	Application Kind Code Text	D AIT
AN	Accession Number	D AN
CGP	Citing Patent Information	D CGP
CHG	Changes (Indicator for changes in the last update)	D CHG
CPC	Cooperative Patent Classification	D CPC
DAV	Data Availability	D DAV
DF	Date in Force	D DF

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
DS	Designated States	D DS
DT (TC)	Document Type	D DT
ED	Entry Date	D ED
EDP	Entry Date Patent	D EDP
EW	Entry Week	D EW
FA	Field Availability	D FA
FCL (JPC)	Japanese Patent Classification (FI-Terms)	D FCL
FDT	Filing Details	D FDT
FN	Family Number	D FN
FTRM (FTERM, FTCLA, JPCLA)	Japanese Patent Classification (F-Terms)	D FTRM
GI	Graphic Image	D GI
IC	International Patent Classification (ICM, ICS)	D IC
ICA	IPC, Additional (supplementary)	D ICA
ICI	IPC, Index (complementary)	D ICI
ICM	IPC, Main	D ICM
ICS	IPC, Secondary	D ICS
IN	Inventor	D IN
IN.CNY	Inventor, Country	D INS
INA	Inventor Address	D INA
INCL	US National Classification, Issued	D INCL
INCLM	US National Classification, Issued (main)	D INCL
INCLS	US National Classification, Issued (secondary)	D INCL
INS	Inventor INPADOC Standard	D INS
IPCI	IPC, Initial	D IPCI
IPCR	IPC, Reclassified	D IPCR
LA	Language	D LA
LAF	Language of Filing	D LAF
LCL	Locarno Classification	D LCL
NCL	US National Classification, Current	D NCL
NCLM	US National Classification, Current (main)	D NCL
NCLS	US National Classification, Current (secondary)	D NCL
OCL	Other National Classifications	D OCL
PA (CS)	Patent Assignee	D PA
PAA	Patent Assignee Address	D PAA
PA.CNY	Patent Assignee, Country	D PAS
PAS	Patent Assignee INPADOC Standard	D PAS
PI (PN) (2)	Patent Information	D PI
PIT	Patent Information Publication Type	D PIT
PNC.G	Citing Patent Number Count	D PNC.G
PNK	Patent Number/Kind Code	D PNK
PRAI (PRN) (2)	Priority Information	D PRAI
PRAIT	Priority Kind Text	D PRAIT
REAI	Referenced Application Information	D REP
REC (RE.CNT)	Reference Count	D REC
REN (NPL)	Referenced Non-Patent Literature	D REN
REP	Referenced Patents	D REP
REXP	Non-Patent Literature XP-Document Number	D REXP
STA	Status	D STA
TI	Title	D TI
TL	Title Language	D TL
UP	Update Date	D UP
UW	Update Week (INPADOC Week)	D UW
XPD	Calculated Expiration Date	D XPD
XPY	Calculated Expiration Year	D XPY

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
ABS (1) ALL (2) ALLG ALLO (2) IALL (2) IALLG BIB (2)	AN, AB, ABDE, ABES, ABFR, ABOL, ABEQ BIB, all Abstracts, IND, FA, CHG ALL, plus graphic image ALL, with original data in UTF-8 characters ALL, indented with text labels IALL, plus graphic image	D ABS D ALL D ALLG D ALLO D IALL D IALLG D BIB
IBIB (2) BRIEF BRIEFG APPS (2) CPC.TAB IND IPC IPC.TAB LS LS2 LSO LSUP MAX (2) MAXG IMAX (2) IMAXG MAXO (2) MAXO2 (2) PATS (2) PI.PDF	AN, ED, EW, UP, UW, FN, UPFC, TI, TL, IN, INS, INA, PA, PAS, PAA, DT, LA, LAF, PI, PIT, DAV, STA, DF, DS, XS, AI, AIT, PRAI, PRAIT, XPD, REC (The default format is BIB.M) BIB, indented with text labels TI, INS, PAS, IPCI, IPCR, CPC, NCL, INCL, FTRM, FCL, LCL, PI, AI, PRAI, abstracts BRIEF, plus graphic image Application Number Group (AI, PRAI) CPC, CPC.KW, CPC.ACD, CPC.VER, in tabular format AN, ED, EW, UP, UW, IPC, CPC, NCL, INCL, FTRM, FCL, LCL, OCL ICM, ICS, ICA, ICI, IPCR, IPCI IPC, IPC.KW, IPC.ACD, IPC.VER, in tabular display AN, UPLS, Legal Status Legal Status, detailed version with display headers Legal Status, Original Language Last LS Update ALL.M plus RE, CGP, LS MAX, plus graphic image MAX, indented with text labels IMAX, plus graphic image MAX, with original data in UTF-8 characters MAXO, plus display of special characters in the abstract Patent Number Group (PI, REP) National family PI information plus hyperlinks to the original documents (pdf) in espacenet	D IBIB D BRIEF D BRIEFG D APPS D CPC.TAB D IND D IPC D IPC.TAB D LS D LS2 D LSO D LSUP D MAX D MAXG D IMAX D IMAXG D MAXO D MAXO2 D PATS D PI.PDF
RE SCAN (3) STD (2) STDG	Cited References (REP, REXP, REAI, REN) TI latest publication (random display without answer number) BIB, IND STD, plus graphic image	D RE D SCAN D STD D STDG
TRIAL (TRI, FREE, SAMPLE, SAM) HIT KWIC OCC	TI, IPC, CPC, NCL, INCL, FTRM, FCL, LCL, FA Hit term(s) and field(s) Up to 50 words before and after hit term(s) (KeyWord-In-Context) Number of occurrences of hit term(s) and field(s) in which they occur	D TRIAL D HIT D KWIC D OCC

(1) ABEQ only for records entered or updated after week 200740.

(2) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.

(3) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

FAMILY DISPLAY and PRINT Formats

Format	Content	Examples
TIPI.F	TI + PI for all patent family members	D TIPI.F
PILS.F (1,4)	PI + LS for all patent family members	D PILS.F
BIBLS.F (1)	BIB + LS for all patent family members	D BIBLS
CFAM (1)	Condensed family table with publication numbers and dates	D CFAM
CFAM2 (1)	Condensed family table with PI, AI, PRAI	D CFAM2
CITN	RE + CGP for all patent family member	D CITN
DFAM (1,2)	FAM, delimited for post processing	D DFAM
DFAM.AD	DFAM, sorted by Application Date	D DFAM.AD
DFAM.AP	DFAM, sorted by Application Number	D DFAM.AP
DFAM.PD	DFAM, sorted by Patent Date	D DFAM.PD
DFAM.PN	DFAM, sorted by Patent Number	D DFAM.PN
DFAM.PRD	DFAM, sorted by Priority Date	D DFAM.PRD
EFAM (1)	FAM, but the priority information constitutes the header	D EFAM
EFAM.PRD	EFAM, sorted by Priority Date	D EFAM.PRD
FAM (1)	AN, table of patent family information (PI, AI, PRAI) and relationships	D FAM
FAM.PRD	AN, table of patent family information, sorted by Priority Date	D FAM.PRD
FAMLS (1)	Comprises the family table CFAM2 plus a list of all legal status entries, sorted by legal status date LSD	D FAMLS
FAM2 (1)	AN, table of patent family information, another order	D FAM2
FFAM (1)	STD + LS for each member of the family	D FFAM
FFAM.PC (1,3)	FFAM for a specified country only	D FFAM.PC
FFAMG	FFAM, plus graphic image	D FFAM.G
IFAM (1)	Combines indented FAM and IMAX.F	D IFAM
IFAM2	IFAM without abstract, classification and citation	D IFAM2
IFAMG	IFAM, plus graphic image	D IFAMG
LFAM (1)	AN, PI, LSUP for all members of a patent family	D LFAM
MFAM (1)	MAX for each family member	D MFAM
MFAMG	MFAM, plus graphic image	D MFAMG
MFAM.PC (1,3)	MFAM for a specified country only	D MFAM.PC
PICITN	PI + CITN for all patent member family	D PICITN
SFAM (1)	Display of the EPO 'simple patent family' (SFN) within the INPADOC patent family table	D SFAM
UPALL	Table of update dates (AN, FN, UPFC, UPBB, UPCC, ED, EDP, UPFB, UPFP, UPFD, EDF, UPFL)	D UPALL

(1) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.

(2) SET LINE 100 is recommended.

(3) PC = all patent countries.

(4) In format PILS legal status is displayed without the information PRI, APP, and PUB.

FAMILY DISPLAY and PRINT Formats – Weekly SDI

Format	Content	Examples
FFAMED (1) FFAMED.PC (1,2) FFAMUP (1) FFAMUP.PC (1,2)	STD for new publications and/or LSUP for each updated family FFAMED for a specific country only STD + LS for each updated family FFAMUP for a specific country only	D FFAMED D FFAMED.PC D FFAMUP D FFAMUP.PC
IFAMED (1) IFAMUP (1) LFAMUP (1) LFAMUP.PC (1,2)	Indented FFAMED plus patent family table Indented FFAMUP plus patent family table AN, PI, LSUP for all updated members of a patent family LFAMUP for a specific country only	D IFAMED D IFAMUP D LFAMUP D LFAMUP.PC

- (1) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.
- (2) PC = AR, AT, AU, BE, BR, CA, CH, CN, DE, DK, EP, ES, FI, FR, GB, IL, IT, JP, KR, MX, NL, NO, RU, SE, TW, US, WO

FAMILY DISPLAY and PRINT Formats – Monthly SDI

Format	Content	Examples
FFAMED4 (1) FFAMUP4 (1) IFAMED4 (1) IFAMUP4 (1) LFAMUP4 (1)	STD for new publications and/or LSUP for each updated family STD + LS for each updated family Indented FFAMED4 plus patent family table Indented FFAMUP4 plus patent family table AN, PI, LSUP for all updated members of a patent family	D FFAMED4 D FFAMUP4 D IFAMED4 D IFAMUP4 D LFAMUP4

- (1) Application, patent, and priority number are available in STN and Derwent format. The format for DISPLAY, PRINT, SELECT, and SORT is set using the SET PATENT command. STN is the default format. Enter SET PAT DERWENT to change to the Derwent format. To reset to the STN format, enter SET PAT STN.

Sorting within the PATENT FAMILY DISPLAY Formats

Format	Content
FAM DFAM EFAM FFAM LFAM CFAM	PRN (Priority Number) PRN (Priority Number) PRN (Priority Number) PN (Patent Number) of the highest level PN (Patent Number) of the highest level AP (Application Number)

Sorting within the PATENT FAMILY DISPLAY Formats

You can define the sort parameter in family display formats. Depending on the formats used, options are priority date (.PRD), publication date (.PD), patent number (.AP), application date (.AD). The following combinations are available.

Format	Content
FAM.PRD CFAM.PD DFAM.PRD DFAM.AP DFAM.AD DFAM.PN DFAM.PD EFAM.PRD	Priority Date Publication Date Priority Date Application Number Application Date Patent Number Patent/Publication Date Priority Date

INPADOCDB**SELECT, ANALYZE, and SORT Fields**

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

The SELECT/ANALYZE command extracts terms from all publication levels.

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract in English	AB	Y	Y
Abstract in French	ABFR	Y (2)	Y
Abstract in German	ABDE	Y (2)	Y
Abstract in Other Language	ABOL	Y (2)	Y
Abstract in Spanish	ABES	Y (2)	Y
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Kind Code	AK	Y	Y
Application Kind Code Text	AIT	Y	Y
Application Number	AP (AI)	Y (3)	Y
Application Number Group	APPS	Y (3,4)	N
Application Year	AY	Y	Y
Calculated Expiration Day	XPD	Y	Y
Calculated Expiration Year	XPY	Y	Y
Changes (Indicator for the changes in the last update)	CHG	Y	N
Cited Application Country	AC.D	Y	N
Cited Application Kind Code	AK.D	Y	N
Cited Application Number	AP.D	Y	N
Citing Patent Country	PC.G	Y	N
Citing Patent Number	PN.G	Y	N
Citing Patent Number Count	PNC.G	Y	N
Cooperative Patent Classification	CPC	Y	N
Date in Force	DF	Y	Y
Designated State	DS	Y	N
Document Type	DT (TC)	Y	Y
Entry Date	ED	Y	N
Entry Date Patent	EDP	Y	N
Entry Week	EW	Y	N
International Patent Classification	IC	Y	N
International Patent Classification	IPC	Y	Y
Inventor	IN (AU)	Y	Y
Inventor, Country	IN.CNY	Y	Y
Inventor Address	INA	Y	Y
Inventor INPADOC Standard	INS	Y	Y
IPC, Additional (supplementary)	ICA	Y	Y
IPC, Advanced Level Symbols	IPC.A	Y (5)	N
IPC, Advanced Level Symbols for Invention	IPC.AI	Y (5)	N
IPC, Core Level Symbols	IPC.C	Y (5)	N
IPC, Core Level Symbols for Invention	IPC.CI	Y (5)	N
IPC, Index (complementary)	ICI	Y	Y
IPC, Initial	IPCI	Y (5)	N
IPC, Main	ICM	Y	Y
IPC, Reclassified	IPCR	Y (5)	N
IPC, Secondary	ICS	Y	Y

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Japanese Patent Classification (F-Terms)	FTRM	Y	N
Japanese Patent Classification (FI-Terms)	FCL	Y	N
Language	LA	Y	Y
Language of Filing	LAF	Y	Y
Locarno Classification	LCL	Y	Y
Legal Status Code	LSC	Y	N
Legal Status Code Category	LSC2	Y	N
Legal Status Code Country	LSCC	Y	N
Legal Status Date INPADOC GAZETTE	LSD	Y	N
Legal Status Free Format Text	LSFT	Y	N
Legal Status IPC	LSIC	Y	N
Legal Status Patent Assignee	LSPA	Y	N
Legal Status Patent Inventor	LSIN	Y	N
Legal Status Patent Opponent	LSOP	Y	N
Legal Status Payment Year	LSPMY	Y	N
Legal Status Publication Country	LSPC	Y	N
Legal Status Publication Date	LSPD	Y	N
Legal Status Publication Number	LSPN	Y	N
Legal Status Representative/Agent	LSAG	Y	N
Legal Status SPC Number	LSSPC	Y	N
Legal Status SPC, Expiry Date	LSSPC.XD	Y	N
Legal Status SPC, Extension Date	LSSPC.EX	Y	N
Legal Status SPC, Filing Date	LSSPC.FD	Y	N
Occurrence Count of Hit Terms	OCC	N	Y
Other National Classifications	OCL	Y	Y
Patent Assignee	PA (CS)	Y	Y
Patent Assignee Address	PAA	Y	Y
Patent Assignee INPADOC Standard	PAS	Y	Y
Patent Assignee, Country	PA.CNY	Y	Y
Patent Country	PC	Y	Y
Patent Information Publication Type	PIT	Y	Y
Patent Kind Code	PK	Y	Y
Patent Number	PN (PI)	Y (3)	Y
Patent Number/Kind Code	PNK	Y	N
Patent Number Group	PATS	Y (3,6)	Y
Pre-IPC8 Symbols from the ICM and first IPC8 values from 2006 to the present	IPC.F	Y (5)	Y
Priority Country	PRC	Y	Y
Priority Country, First	PRCF	Y	Y
Priority Country, First of PCT Priorities	PRCF.WO	Y	Y
Priority Date	PRD	Y	Y
Priority Date, First	PRDF	Y	Y
Priority Kind Code	PRK	Y	Y
Priority Kind Text	PRAIT	Y	Y
Priority Number	PRN (PRAI)	Y (3)	Y
Priority Year	PRY	Y	Y
Priority Year, First	PRYF	Y (7)	Y
Publication Date	PD	Y	Y
Publication Year	PY	Y	Y
Reference Count	REC (RE.CNT)	Y	N
Referenced Non-Patent Literature	REN	Y	Y
Referenced Non-Patent Literature XP-Document Number	REXP	Y	Y
Referenced Patent Country	RPC (PC.D)	Y	N

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Referenced Non-Patent Literature	REN	Y	Y
Referenced Non-Patent Literature XP-Document Number	REXP	Y	Y
Referenced Patent Country	RPC (PC.D)	Y	N
Referenced Patent Date	RPD (PD.D)	Y	N
Referenced Patent Kind Code	RPK (PK.D)	Y	N
Referenced Patent Number	RPN (PN.D)	Y	N
Referenced Patent Year	RPY (PY.D)	Y	N
Referenced Patents	REP	Y	Y
Title	TI	Y (default)	Y
Title Language	TL	Y	Y
Update Date	UP	Y	N
Update Week	UW	Y	N
US National Classification, Current	NCL	Y	Y
US National Classification, Current (main)	NCLM	Y	N
US National Classification, Current (secondary)	NCLS	Y	N
US National Classification, Issued	INCL	Y	Y
US National Classification, Issued (main)	INCLM	Y	N
US National Classification, Issued (secondary)	INCLS	Y	N

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- (2) Appends /AB to the terms created by SELECT.
- (3) SELECTed and SORTed application, priority and patent numbers are in the format set by the Messenger SET PATENT command, either DERWENT or STN.
- (4) Selects or analyzes AP, PRN, and appends /APPS to the terms created by SELECT.
- (5) Appends /IPC to the terms created by SELECT.
- (6) Selects or analyzes /PN, /RPN with /PATS appended to the terms created by SELECT.
- (7) SELECT or ANALYZE HIT are not valid with this field.

Update Codes (for SDI also)**Update codes or entry dates associated with records**

Field Name	Search Code	Search Examples	Display Codes
Entry Date	/ED	S L1 AND ED>DEC 2006	ED
Entry Date + Legal Status Update	/EDLS	S EDLS = JAN 2008	not displayed
Entry Date Patent (new record)	/EDP	S 20061026/EDP	EDP, UPALL
Entry Date Priority	/EDPR	S 29 JAN 2009/EDPR	PRAI
Update Date	/UP	S 20070102/UP	LS
Update Legal Status	/UPLS	S 20070222/UPLS	LS
All updates of a record	/UPM	S 20070215/UPM	not displayed

Update codes or entry dates associated with patent families (1,2)

Field Name	Search Code	Search Examples	Display Codes
Entry Date new patent family	/EDF	S L1 AND EDF>21 MAR 2007	UPALL
All changes in a patent family	/UPFA	S L1 AND 20070329/UPFA	not displayed
Any change of a bibliographic element in a patent family	/UPFB	S L1 AND 20070215/UPFB	UPALL
Update Date for combined or split Patent Family (3)	/UPFC	S L1 AND UPFC=OCT 2009	UPFC
Entry of a new database record (document) into a patent family (level 1)	/UPFD	S L1 AND 20070215/UPFD	UPALL
Entry of a new publication and changes in legal status	/UPFE	S L1 AND 20070321/UPFE	not displayed
Any change of a legal status in a patent family	/UPFL	S L1 AND 20070321/UPFL	UPALL
Entry of a new publication level into a patent family	/UPFP	S L1 AND 20070222/UPFP	UPALL

- (1) Available since February 2007.
- (2) Special display formats available for monitoring patent families weekly.
- (3) Available since September 2009.

Sample Records

DISPLAY MAXG

```

AN      24180089 INPADOCDB UW 201212
FN      13550763
TI      Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.
        Coated sheet cutting method and apparatus.
        Procede et appareil pour la coupe d'une feuille revetue.
TL      German; English; French
IN      KAWAI, HIROKAZU
INS     KAWAI HIROKAZU, JP
PA      FUJI PHOTO FILM CO., LTD.
PAS     FUJI PHOTO FILM CO LTD, JP
DT      Patent
PI      EP 1488896           A1 20041222  English
PIT     EPA1 APPLICATION PUBLISHED WITH SEARCH REPORT
DAV     20041222  examined-printed-without-grant
STA     PRE-GRANT PUBLICATION
DS      R:           DE FR GB
AI      EP 2004-13971       A   20040615
AIT     EPA Patent application
PRAI    JP 2003-174783      A   20030619  (JPA, 20070816, Y)
        JP 2003-174784      A   20030619  (JPA, 20070816, Y)
PRAIT   JPA Patent application
REP     JP 2001138285       A           (SEA, npl, Cat: Y)
        SONY CORP
        JP 06168444         A           (SEA, npl, Cat: Y)
        MATSUSHITA ELECTRIC IND CO LTD
REXP    XP000510813  (SEA, Cat: A)
REN     (1) PATENT ABSTRACTS OF JAPAN vol. 2000, no. 22, 9 March 2001
        (2001-03-09) & JP 2001 138285 A (SONY CORP), 22 May 2001 (2001-05-22)
        (SEA, Cat: Y)

```

INPADOCDB

(2) PATENT ABSTRACTS OF JAPAN vol. 0185, no. 05 (P-1803), 21 September 1994 (1994-09-21) & JP 6 168444 A (MATSUSHITA ELECTRIC IND CO LTD), 14 June 1994 (1994-06-14) (SEA, Cat: Y)

(3) KLEIN H: "LANGSSCHNEIDEN VON BAHNFORMIGEN MATERIALIEN DER KREISMESSER-SCHERENSCHNITT UND SEINE OPTIMALE EINSTELLUNG FUR DAS LANGSSCHNEIDEN BAHNFORMIGER MATERIALIEN (TEIL 3)" COATING, VERLAG COATING THOMAS & CO, CH, vol. 28, no. 5, 1 May 1995 (1995-05-01), pages 176-179, XP000510813 ISSN: 0590-8450 (SEA, Cat: A)

REC 5. THERE ARE 5 CITED REFERENCES (2 PATENT, 3 NON PATENT) AVAILABLE FOR THIS RECORD.

IC.V 7

ICM B26D001-24

IPCR B26D0001-24 [I,A]; B26D0007-26 [N,A]

CPC B26D0001-245; B26D0007-2635; B26D2001-0053

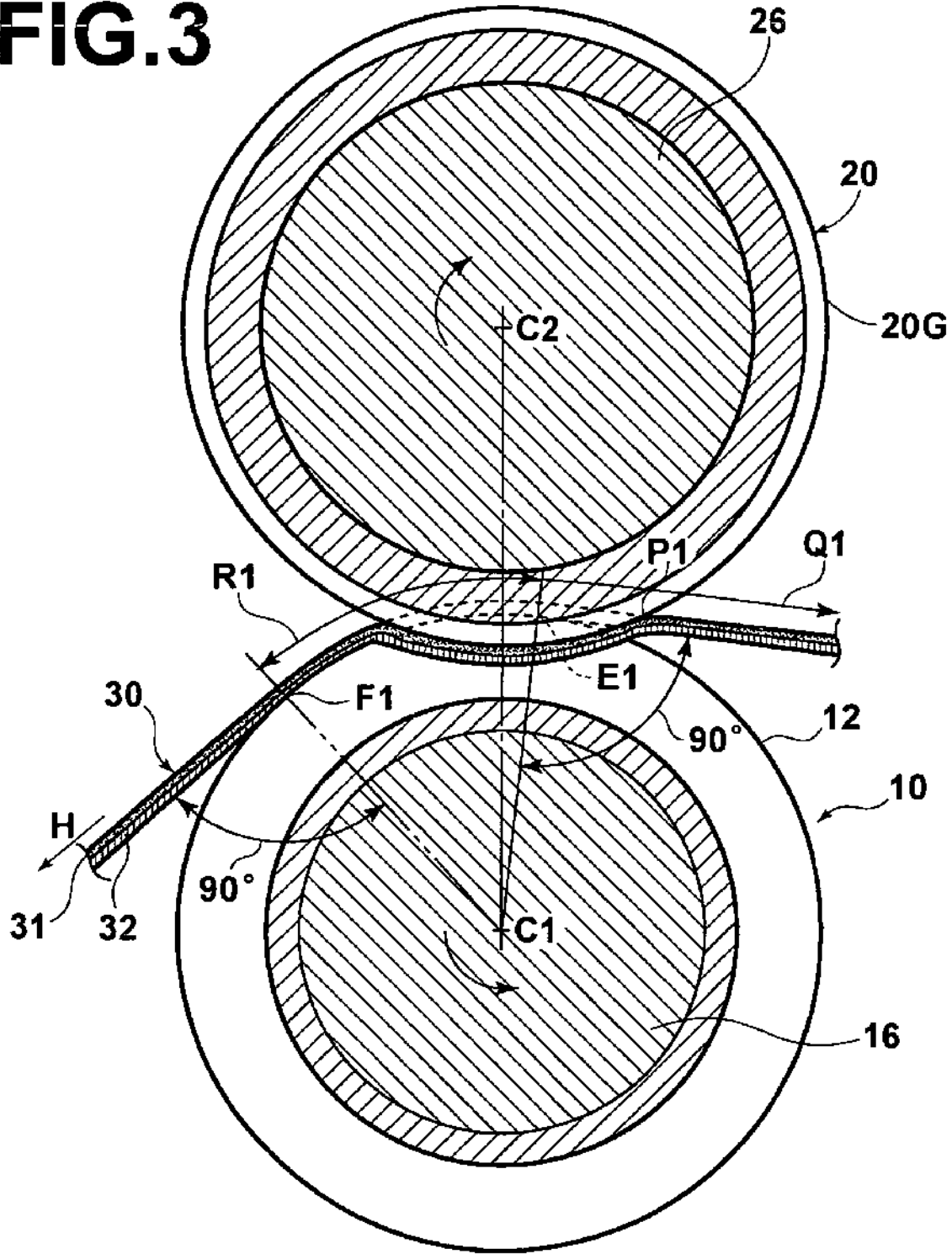
AB A discoid lower blade and a discoid upper blade, having a sharper knife angle compared with that of the lower blade, are arranged such that rotational axes thereof are parallel to each other, and portions of the blades overlap one another in the direction that the rotational axes extend. A sheet with a coating layer on one side is fed through and shear-cut between the upper and lower blades in the direction perpendicular to the rotational axes, with the surface of the sheet opposite the coating layer in contact with a periphery of the lower blade while the blades are rotated. When the sheet is shear-cut, a contact start position, where contact between the sheet and the upper blade starts, is positioned upstream in the feed direction of the sheet but outside a contacting area of the sheet, where the sheet contacts the periphery of the lower cutting blade. Alternatively, the contact start position starts within the contacting area and an overlap between a part of the upper cutting blade and a part of the lower cutting blade is maintained less than 1.5 mm.
<IMAGE>.

AL English

AS EPO

FA AB; AI; AN; DAV; CPC; DS; DT; ICM; IN; INS; IPC; IPCR; LA; PA; PAS; PI; PIT; PRAI; REN; REP; REXP; TI

FIG.3



EPA1

AN 24180089 INPADOCDB UW 201212

FN 13550763

TI Verfahren und Vorrichtung zum Schneiden eines beschichteten Blattes.
Coated sheet cutting method and apparatus.

INPADOCDB

Procédé et appareil pour la coupe d'une feuille revêtue.
 TL German; English; French
 IN KAWAI, HIROKAZU
 INS KAWAI HIROKAZU, JP
 PA FUJI PHOTO FILM CO., LTD.
 PAS FUJI PHOTO FILM CO LTD, JP
 DT Patent
 PI EP 1488896 B1 20061004 English
 PIT EPB1 PATENT SPECIFICATION
 DAV 20061004 printed-with-grant
 STA GRANTED
 DS R: DE FR GB
 AI EP 2004-13971 A 20040615
 AIT EPA Patent application
 PRAI JP 2003-174783 A 20030619 (JPA, 20070816, Y)
 JP 2003-174784 A 20030619 (JPA, 20070816, Y)
 PRAIT JPA Patent application
 XPD 20240615
 IPCI B26D0001-24 [I,A]
 IPCR B26D0007-26 [N,A]
 CPC B26D0001-245; B26D0007-2635; B26D2001-0053
 FA AI; AN; DAV; CPC; DS; DT; IN; INS; IPC; IPCI; IPCR; LA; PA; PAS; PI; PIT;
 PRAI; TI; XPD

LEGAL STATUS

AN 24180089 INPADOCDB
 20041222 EPAK + DESIGNATED CONTRACTING STATES:
 EP A1
 AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IT LI LU
 MC NL PL PT RO SE SI SK TR
 20041222 EPAX + EXTENSION OF THE EUROPEAN PATENT TO
 AL HR LT LV MK
 20050803 EP17P + REQUEST FOR EXAMINATION FILED
 20050603
 EXA Examination, Search Report
 20050914 EPAKX + PAYMENT OF DESIGNATION FEES
 DE FR GB
 20061004 EPAK + DESIGNATED CONTRACTING STATES:
 EP B1
 DE FR GB
 20061004 EPREG REFERENCE TO A NATIONAL CODE
 GBFG4D + GB: EUROPEAN PATENT GRANTED
 20061116 EPREF CORRESPONDS TO:
 DE 602004002620 P 20061116
 20070314 EPRAP2 TRANSFER OF RIGHTS OF AN EP PUBLICATION
 FUJIFILM CORPORATION
 CHG Change of Owner, Inventor, Applicant
20070315
 20070411 EPREG REFERENCE TO A NATIONAL CODE
 GB732E GB: AMENDMENTS TO THE REGISTER IN RESPECT OF CHANGES OF
 NAME OR CHANGES AFFECTING RIGHTS (SECT. 32/1977)
 CHG Change of Owner, Inventor, Applicant
20070419
 20070420 EPET + FR: TRANSLATION FILED
20070510
 20070912 EP26N + NO OPPOSITION FILED
 20070705
20070914
 20070928 EPREG REFERENCE TO A NATIONAL CODE
 FRTP FR: TRANSMISSION OF PROPERTY

CHG Change of Owner, Inventor, Applicant
20071011
 20070928 EPREG REFERENCE TO A NATIONAL CODE
 FRCD FR: CHANGE OF NAME OR COMPANY NAME
 CHG Change of Owner, Inventor, Applicant
20071011
 20120731 EPPGFP + POSTGRANT: ANNUAL FEES PAID TO NATIONAL OFFICE
 DE: 20120613
 Payment Year: 09
20120802
 20120831 EPPGFP + POSTGRANT: ANNUAL FEES PAID TO NATIONAL OFFICE
 GB: 20120613
 Payment Year: 09
20120906
 20120831 EPPGFP + POSTGRANT: ANNUAL FEES PAID TO NATIONAL OFFICE
 FR: 20120619
 Payment Year: 09
20120906

DISPLAY FAM

PATENT FAMILY INFORMATION
 AN 24180089 INPADOCDB

+-----PRAI-----+			+-----AI-----+		
JP 2003-174783	A	20030619	CN 2004-10059710	A	20040617
			DE 2004-602004002620	T	20040615
			EP 2004-13971	A	20040615
			JP 2003-174783	A	20030619
			US 2004-868808	A	20040617
JP 2003-174784	A	20030619	CN 2004-10059710	A	20040617
			DE 2004-602004002620	T	20040615
			EP 2004-13971	A	20040615
			JP 2003-174784	A	20030619
			US 2004-868808	A	20040617
+-----AI-----+			+-----PI-----+		
CN 2004-10059710	A	20040617	CN 1572446	A	20050202
DE 2004-602004002620	T	20040615	DE 602004002620	D1	20061116
EP 2004-13971	A	20040615	EP 1488896	A1	20041222
			EP 1488896	B1	20061004
JP 2003-174783	A	20030619	JP 2005007524	A	20050113
JP 2003-174784	A	20030619	JP 2005007525	A	20050113
US 2004-868808	A	20040617	US 20040255743	A1	20041223

2 priorities, 6 applications, 7 publications

DISPLAY ALL

AN 51399732 INPADOCDB UP 20120614 UW 201224
 FN 34407383
 TI Neck fastening for mechanical line-fastening of insulating material and sealing tracks on flat roofs consists of rail with holes and fastenings formed from screws anchored onto rail bottom and supported with head on rail.
 Kehlbelegung fuer die mechanische Linienbefestigung von Daemmmaterialien und Abdichtungsbahnen auf Flachdaechern.
 TL English; German

INPADOCDB

PA HARALD ZAHN GMBH
 PAS ZAHN HARALD GMBH, DE
 DT Patent
 PI DE 102005022624 A1 20061123
 PIT DE A1 DOC. LAID OPEN (FIRST PUBLICATION)
 DAV 20061123 unexamined-printed-without-grant
 STA PRE-GRANT PUBLICATION
 AI DE 2005-102005022624 A 20050517
 AIT DEA Patent application
 PRAI DE 2005-102005022624 A 20050517 (DEA, Y)
 PRAIT DEA Patent application
 IPCI E04D0005-14 [I,A]; E04B0001-74 [I,A]; E04D0003-36 [I,A]
 CPC E04D0003-3603; E04D0003-3602; E04D0005-146; F16B0013-00; F16B0043-02
 AB Neck fastening consists of a rail with holes made in the rail bottom and individual fastenings. Fastenings are each formed from a screw (1) which is put in the rail base, supported with its head (3) on the rail and which cuts with its end into the roof bottom or juts into a wall plug anchored into the roof base. From both sides of the hole on the rail narrow positioning edges or noses protrude on which the underside of the screw head lies. When its clamping force is held steady suspended see-saw like between its positioning edges or noses, the rail lies on the underside of the screw head.
 AL English
 AS transcript
 FA AB; AI; AN; DAV; CPC; DT; IPC; IPCI; PA; PAS; PI; PIT; PRAI; TI

DISPLAY BIB RE

AN 59518659 INPADOCDB ED 20091015 EW 200942 UP 20091022 UW 200943
 FN 38441986
 TI Verfahren zur Beschichtung eines metallischen Substrats mit einer Schicht aus niedrig legiertem Stahl.
 Method to coat a metallic substrate with low alloy steel layer.
 Procède de revêtement d'un substrat métallique avec un revêtement a faible alliage d'acier.
 TL German; English; French
 IN CHILDS, CHRISTOPHER; MARCHANT, GEOFFREY
 INS CHILDS CHRISTOPHER, GB; MARCHANT GEOFFREY, GB
 PA SIEMENS AKTIENGESELLSCHAFT
 PAS SIEMENS AG, DE
 DT Patent
 PI EP-----2108476 A1 20091014 English
 PIT EP A1 APPLICATION PUBLISHED WITH SEARCH REPORT
 DAV 20091014 examined-printed-without-grant
 STA PRE-GRANT PUBLICATION
 DS R: AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI
 LT LU LV MC MT NL NO PL PT RO SE SI SK TR
 XS R: AL BA MK RS
 AI 2008EP-000007060 A 20080409
 AIT EPA Patent application
 PRAI 2008EP-000007060 A 20080409 (EPA, 20091015, Y)
 PRAIT EPA Patent application
 REC 6. THERE ARE 6 CITED REFERENCES (5 PATENT, 1 NON PATENT) AVAILABLE FOR THIS RECORD. ALL CITATIONS ARE AVAILABLE IN THE RE FORMAT.
 REP EP 1835189 A2 (SEA, pat, Cat: X) GEN ELECTRIC, US
 EP 1898048 A1 (SEA, pat, Cat: A) HITACHI LTD, JP
 WO 2006111520 A1 (SEA, pat, Cat: A) SIEMENS AG, DE; SHEPHERD ANDREW, GB; WALKER PAUL METHEW, GB

US 4300474 A (SEA, pat, Cat: AD) ROLLS ROYCE
 GB 2052566 A (APP, pat) ROLLS ROYCE
 REXP XP008053341 (SEA, Cat: Y)
 REN (1) NOWOTNY S: "BESCHICHTEN, REPARIEREN UND GENERIEREN DURCH
 PRAEZISIONS-AUFTRAGSCHWEISSEN MIT LASERSTRAHLEN//CLADDING, REPAIR, AND
 FREEFORMING BY BUILD-UP WELDING USING LASER IRRADIATION" VAKUUM IN
 FORSCHUNG UND PRAXIS, WILEY-VCH, WEINHEIM, DE, vol. 14, no. 1, 1 February
 2002 (2002-02-01), pages 33-37, XP008053341 ISSN: 0947-076X (SEA, Cat: Y)
 REC 6. THERE ARE 6 CITED REFERENCES (5 PATENT, 1 NON PATENT) AVAILABLE FOR
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